



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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## Product Summary

$BV_{DSS}$	$R_{DS(ON)}$ Max	$I_D$ Max $T_C = +25^\circ C$
150V	66m $\Omega$ @ $V_{GS} = 10V$	24A

## Features and Benefits

- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- Thermally Efficient Package-Cooler Running Applications
- Low  $R_{DS(ON)}$  – Minimizes On-State Losses
- Low  $Q_g$  – Minimizes Switching Losses
- < 1.1mm Package Profile – Ideal for Thin Applications (PowerDI®)

## Description and Applications

This new generation MOSFET features low on-resistance and fast switching, making it ideal for high-efficiency power-management applications.

- Power-management functions
- DC-DC converters
- Backlighting

PowerDI5060-8/SWP (Type UX)



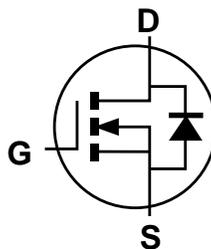
Top View



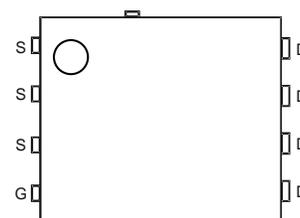
Bottom View

## Mechanical Data

- Package: PowerDI5060-8
- Package Material: Molded Plastic, "Green" Molding Compound  
UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- Terminals: Finish – Matte Tin Annealed over Copper Lead-Frame.  
Solderable per MIL-STD-202, Method 208 Ⓔ③
- Weight: 0.097 grams (Approximate)



Internal Schematic



Top View  
Pin Configuration

**Maximum Ratings** (@  $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			$V_{DSS}$	150	V
Gate-Source Voltage			$V_{GSS}$	$\pm 20$	V
Continuous Drain Current $V_{GS} = 10\text{V}$ (Note 5)	Steady State	$T_C = +25^\circ\text{C}$	$I_D$	24	A
		$T_C = +70^\circ\text{C}$		19	
Pulsed Drain Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)			$I_{DM}$	96	A
Maximum Continuous Body Diode Forward Current (Note 5)			$I_S$	24	A
Pulsed Body Diode Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)			$I_{SM}$	96	A
Avalanche Current, $L = 1\text{mH}$			$I_{AS}$	11.7	A
Avalanche Energy, $L = 1\text{mH}$			$E_{AS}$	68.4	mJ

**Thermal Characteristics**

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 6)	$T_A = +25^\circ\text{C}$	$P_D$	1.9	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	65	$^\circ\text{C/W}$
Total Power Dissipation (Note 7)	$T_A = +25^\circ\text{C}$	$P_D$	3.3	W
Thermal Resistance, Junction to Ambient (Note 7)	Steady State	$R_{\theta JA}$	38	$^\circ\text{C/W}$
Total Power Dissipation (Note 5)	$T_C = +25^\circ\text{C}$	$P_D$	90	W
Thermal Resistance, Junction to Case (Note 5)		$R_{\theta JC}$	1.4	1.4
Operating and Storage Temperature Range		$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

- Notes:
5. Thermal resistance from junction to soldering point (on the exposed drain pad).
  6. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
  7. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1 inch square copper plate.

**Electrical Characteristics** (@  $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 8)</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	150	—	—	V	$V_{GS} = 0V, I_D = 10mA$
Zero Gate Voltage Drain Current	$I_{DSS}$	—	—	1	$\mu A$	$V_{DS} = 120V, V_{GS} = 0V$
Gate-Source Leakage	$I_{GSS}$	—	—	$\pm 100$	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
<b>ON CHARACTERISTICS (Note 8)</b>						
Gate Threshold Voltage	$V_{GS(TH)}$	2	3.2	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	46	66	$m\Omega$	$V_{GS} = 10V, I_D = 20A$
Diode Forward Voltage	$V_{SD}$	—	0.9	1	V	$V_{GS} = 0V, I_S = 20A$
<b>DYNAMIC CHARACTERISTICS (Note 9)</b>						
Input Capacitance	$C_{iss}$	—	814	—	pF	$V_{DS} = 75V, V_{GS} = 0V$ $f = 1MHz$
Output Capacitance	$C_{oss}$	—	84	—		
Reverse Transfer Capacitance	$C_{rss}$	—	3.7	—		
Gate Resistance	$R_g$	—	0.6	—	$\Omega$	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$
Total Gate Charge	$Q_g$	—	11.5	—	nC	$V_{DS} = 75V, I_D = 4.1A$ $V_{GS} = 10V$
Gate-Source Charge	$Q_{gs}$	—	4.6	—		
Gate-Drain Charge	$Q_{gd}$	—	2.8	—		
Turn-On Delay Time	$t_{D(ON)}$	—	5.7	—	ns	$V_{DS} = 75V, V_{GS} = 10V$ $I_D = 4.1A, R_g = 6\Omega$
Turn-On Rise Time	$t_r$	—	17.7	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	15.7	—		
Turn-Off Fall Time	$t_f$	—	12.7	—		
Reverse Recovery Time	$t_{RR}$	—	47	—	ns	$I_F = 4.1A, di/dt = 100A/\mu s$
Reverse Recovery Charge	$Q_{RR}$	—	87	—	nC	

Notes: 8. Short duration pulse test used to minimize self-heating effect.  
 9. Guaranteed by design. Not subject to product testing.

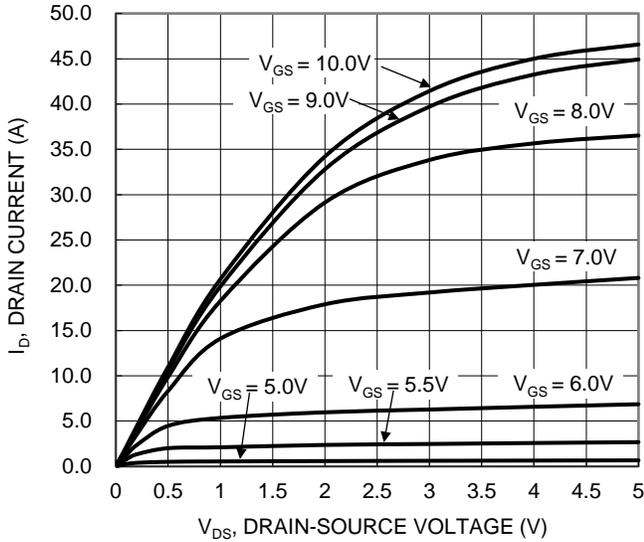


Figure 1. Typical Output Characteristic

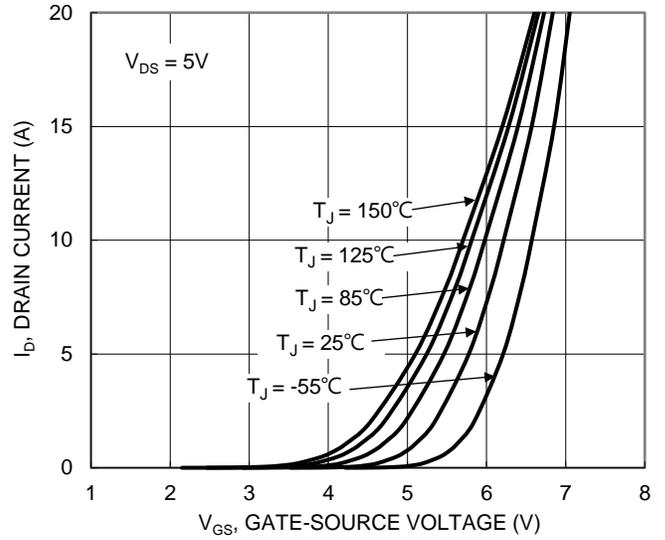


Figure 2. Typical Transfer Characteristic

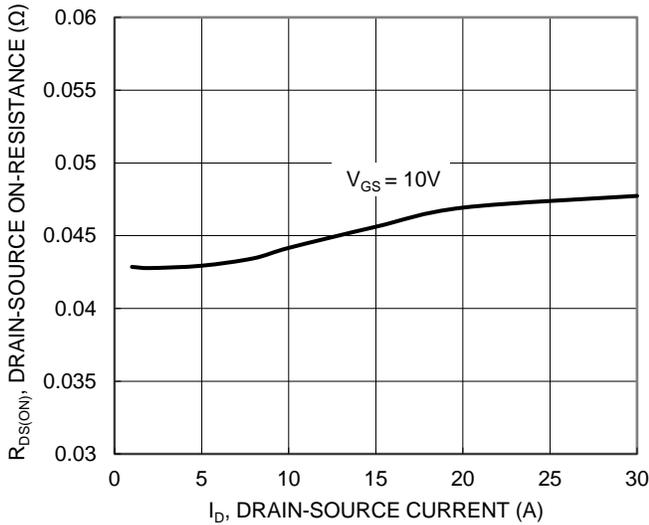


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

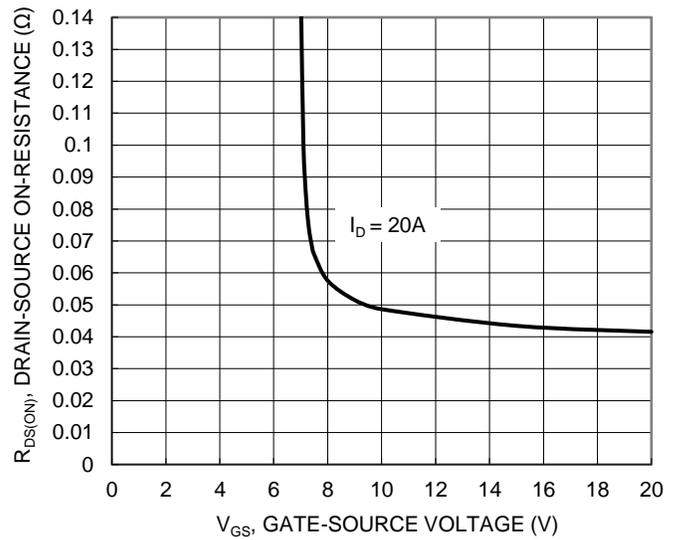


Figure 4. Typical Transfer Characteristic

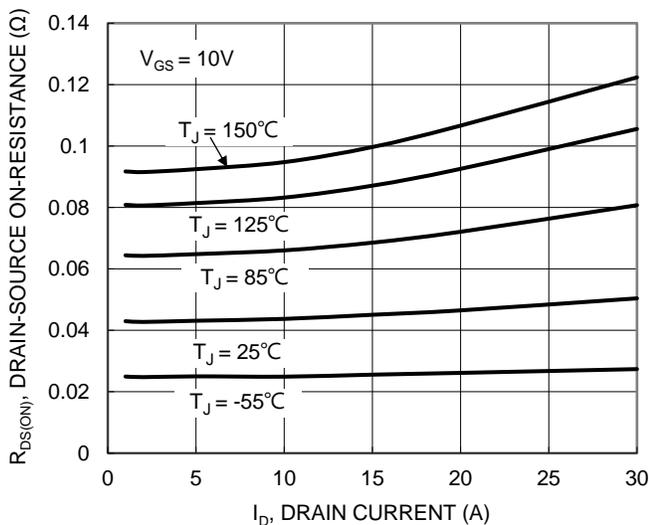


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

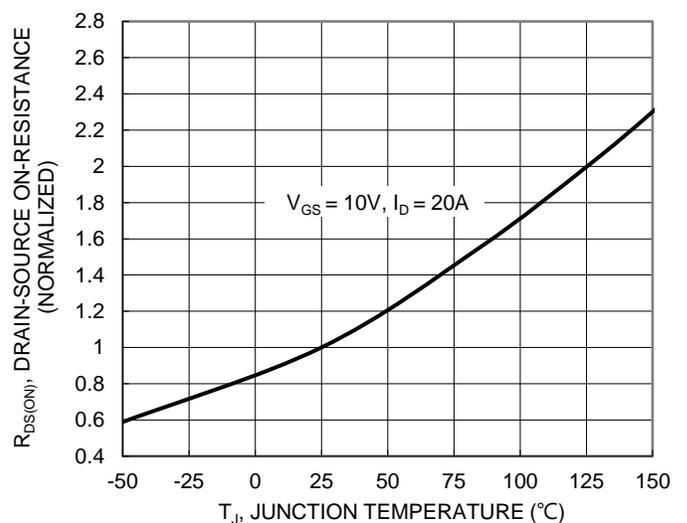


Figure 6. On-Resistance Variation with Junction Temperature

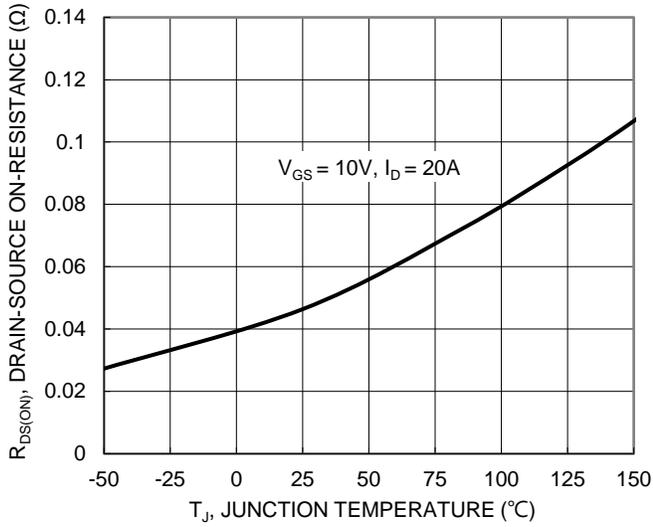


Figure 7. On-Resistance Variation with Junction Temperature

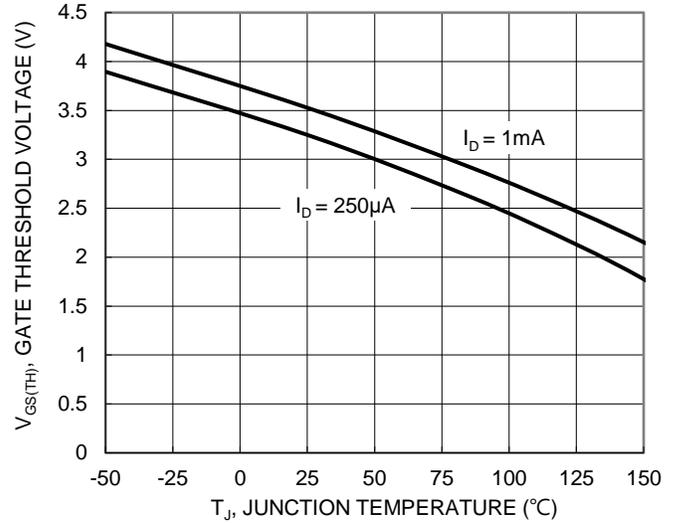


Figure 8. Gate Threshold Variation vs. Junction Temperature

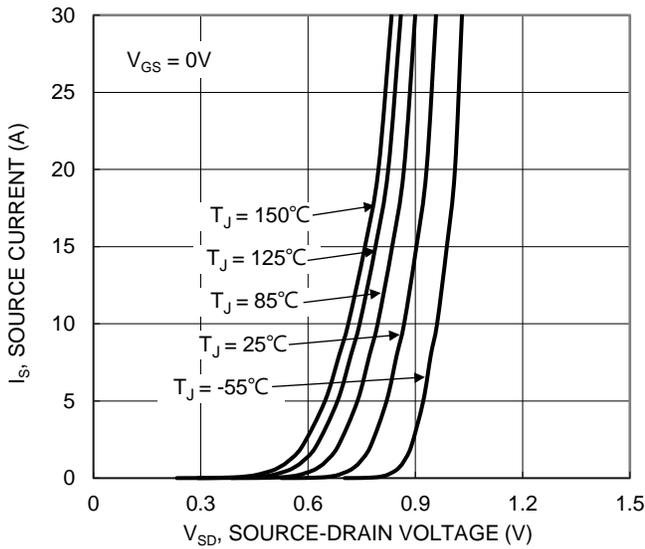


Figure 9. Diode Forward Voltage vs. Current

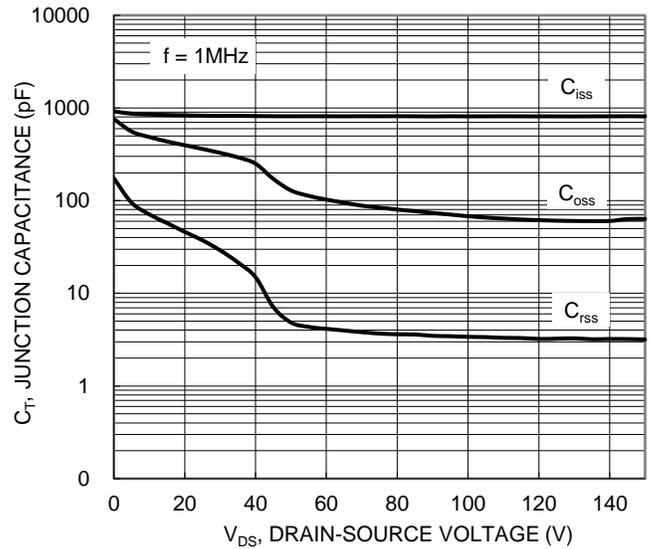


Figure 10. Typical Junction Capacitance

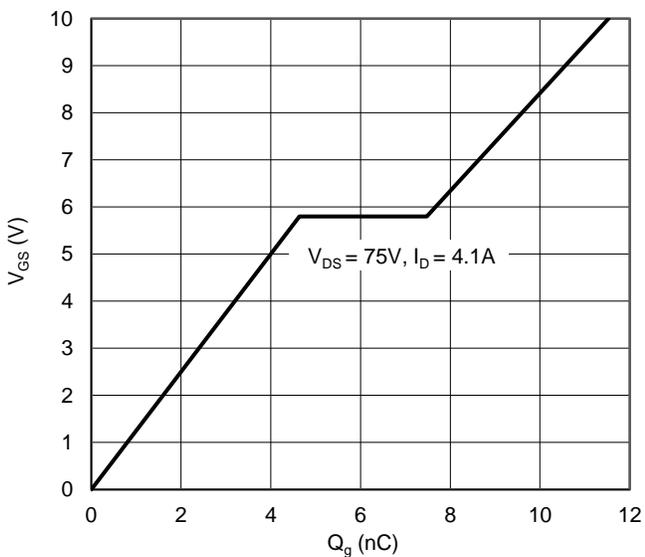


Figure 11. Gate Charge

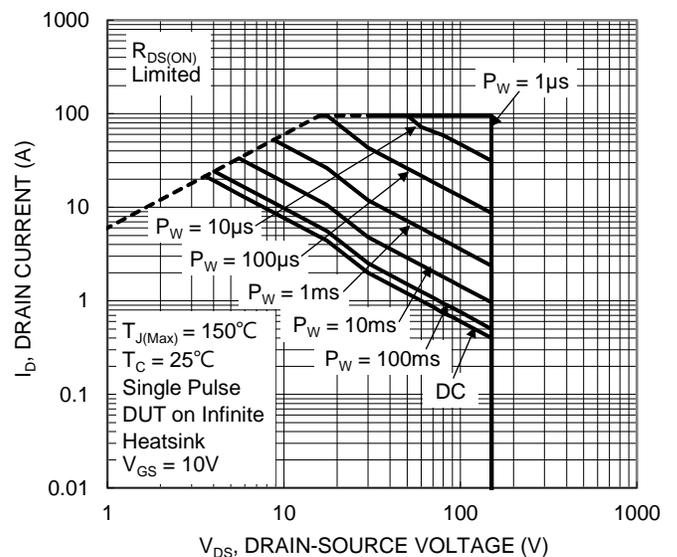


Figure 12. SOA, Safe Operation Area

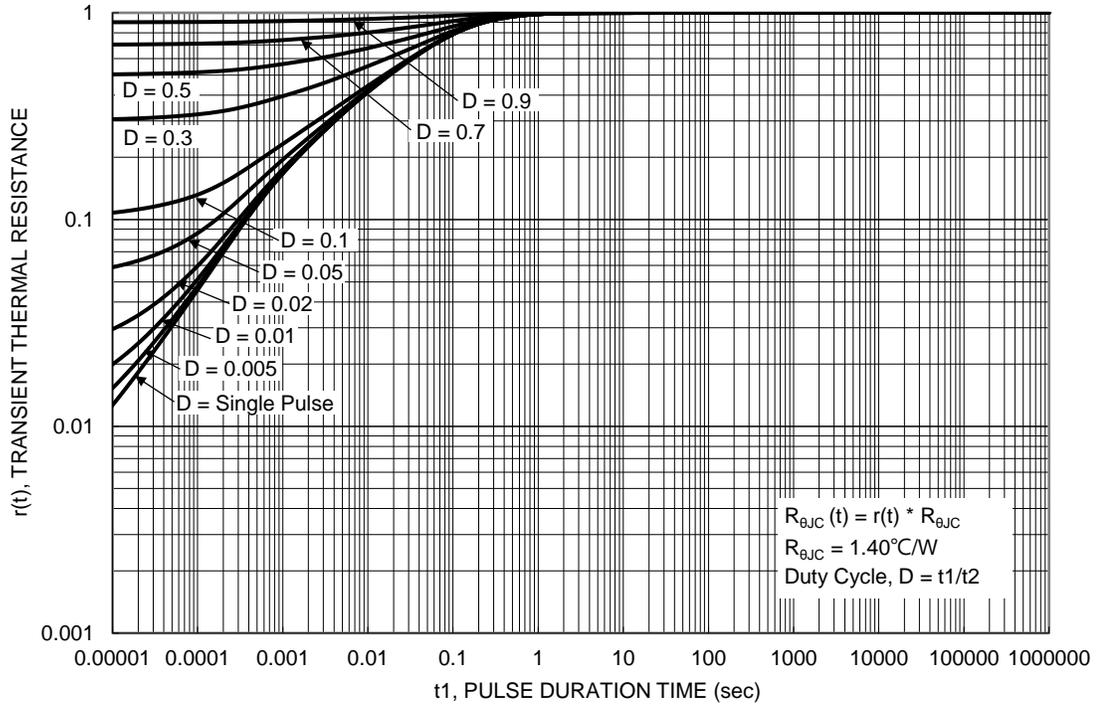


Figure 13. Transient Thermal Resistance

